

Semiconductor devices — Mechanical and climatic test methods —

Part 7: Internal moisture content measurement and the analysis of other residual gases

The European Standard EN 60749-7:2002 has the status of a
British Standard

ICS 31.080.01

National foreword

This British Standard is the official English language version of EN 60749-7:2002. It is identical with IEC 60749-7:2002. It partially supersedes BS EN 60749:1999.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors, which has the responsibility to:

- aid enquirers to understand the text;
- present to the responsible international/European committee any enquiries on the interpretation, or proposals for change, and keep the UK interests informed;
- monitor related international and European developments and promulgate them in the UK.

A list of organizations represented on this committee can be obtained on request to its secretary.

Cross-references

The British Standards which implement international or European publications referred to in this document may be found in the *BSI Catalogue* under the section entitled “International Standards Correspondence Index”, or by using the “Search” facility of the *BSI Electronic Catalogue* or of British Standards Online.

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This British Standard, having been prepared under the direction of the Electrotechnical Sector Policy and Strategy Committee, was published under the authority of the Standards Policy and Strategy Committee on 30 August 2002

Summary of pages

This document comprises a front cover, an inside front cover, the EN title page, pages 2 to 8, an inside back cover and a back cover.

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EUROPEAN STANDARD

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NORME EUROPÉENNE

EUROPÄISCHE NORM

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Partly supersedes EN 60749:1999 + A1:2000 + A2:2001

English version

**Semiconductor devices -
Mechanical and climatic test methods
Part 7: Internal moisture content measurement and
the analysis of other residual gases
(IEC 60749-7:2002)**

Dispositifs à semiconducteurs -
Méthodes d'essais mécaniques
et climatiques
Partie 7: Mesure de la teneur en humidité
interne et analyse des autres gaz
résiduels
(CEI 60749-7:2002)

Halbleiterbauelemente -
Mechanische und klimatische
Prüfverfahren
Teil 7: Messung des inneren
Feuchtegehaltes und Analyse
von anderen Restgasen
(IEC 60749-7:2002)

This European Standard was approved by CENELEC on 2002-07-02. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

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CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

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Foreword

The text of document 47/1597/FDIS, future edition 1 of IEC 60749-7, prepared by IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 60749-7 on 2002-07-02.

This mechanical and climatic test method, as it relates to the internal moisture content measurement and the analysis of other residual gases, is a complete rewrite of the test contained in clause 8, chapter 3 of EN 60749:1999.

The following dates were fixed:

- latest date by which the EN has to be implemented
at national level by publication of an identical
national standard or by endorsement (dop) 2003-04-01
- latest date by which the national standards conflicting
with the EN have to be withdrawn (dow) 2005-07-01

Annexes designated "normative" are part of the body of the standard.

In this standard, annex ZA is normative.

Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 60749-7:2002 was approved by CENELEC as a European Standard without any modification.
